

FCC TEST REPORT

APPLICANT

VR Technology(shenzhen)Limited

PRODUCT NAME

3Wand

MODEL NAME

3Wand G1

TRADE NAME

N/A

BRAND NAME

3Glasses

FCC ID

2AKA6-G1

STANDARD(S)

47 CFR Part 15 Subpart B

TEST DATE

2016-10-31 to 2016-11-09

ISSUE DATE

2016-11-10

SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

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	Change History					
Issue	Issue Date Reason for change					
1.0	2016-11-10	First edition				



Test Report Declaration

Applicant	VR Technology(shenzhen)Limited
Applicant Address	Room4A, Tower A1, Dinital Technology Park ,No.2, Gaoxin South 7th Road,Nanshan District, Shenzhen, China
Manufacturer	BYD Precision Manufacture Company Limited
Manufacturer Address	No.1 Baoping Road, Baolong Industrial Area, Longgang, Shenzhen, Guangdong Province
Product Name	3Wand
Model Name	3Wand G1
Brand Name	3Glasses
HW Version	G1-MB-V4
SW Version	N/A
Test Standards	47 CFR Part 15 Subpart B
Test Result	PASS

Tested by		Wong Valor
**************************************		Wang Dalong (Test Engineer)
Reviewed by	<i>j</i> *	Xiao Xiona
		Xiao Xiong (PMC Manager)
Approved by		Zona Deriv

Zeng Dexin (Technology Manager)



1. Technical Information

Note: Provided by applicant

1.1. Applicant Information

Company: VR Technology(shenzhen)Limited

Address: Room4A, Tower A1, Dinital Technology Park ,No.2, Gaoxin South 7th

Road, Nanshan District, Shenzhen, China

1.2. Equipment under Test (EUT) Description

EUT Type:	3Wand	More	- G M	LAB	ORL
Serial No:	(N/A, marked #1 by test site)	,B	ORLA	Mole	B W
Hardware Version:	G1-MB-V4	.0	LAB	OPL	12
Software Version:	N/A	ORLA	MOL	B	LAB

NOTE:

- 1. The EUT is equipped with a Micro USB port which can be connected to ancillary equipments.
- 2. For a more detailed description, please refer to specification or user's manual supplied by the applicant and/or manufacturer.



2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title		
1	47 CFR Part 15	Radio Frequency Devices		

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Test Date	Result
1	15.107	Conducted Emission	2016.11.02	PASS
2	15.109	Radiated Emission	2016.11.02	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2014.



3. Test Conditions Setting

3.1. Test Mode

The EUT configuration of the emission tests is EUT + PC.

During the measurement, the EUT was connected with the PC via the Micro USB port and kept charging by the PC, meanwhile, it was kept rated output and working normally.

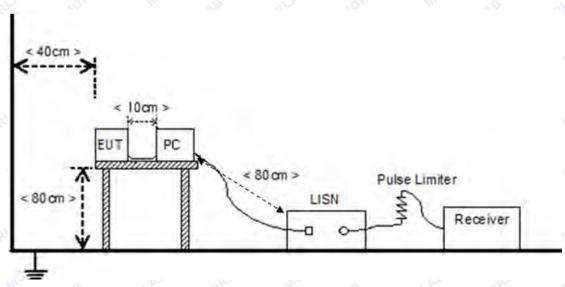




3.2. Test Setup and Equipments List

3.2.1. Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

The power strip or extension cord has been investigated to make sure that the LISN integrity in maintain with respect to the impedance characteristics as prescribed in ANSI C63.4-2014 at Clause 4.3.

B. Equipments List:

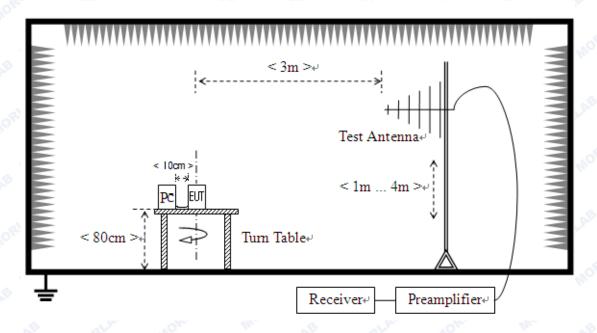
Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9060	001WX11001	2015.11.26	2016.11.25
Receiver	Narda	PMM 9010	595WX11007	2016.01.13	2017.01.12
LISN	Schwarzbeck	NSLK 8127	812744	2016.01.13	2017.01.12
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	2016.01.13	2017.01.12



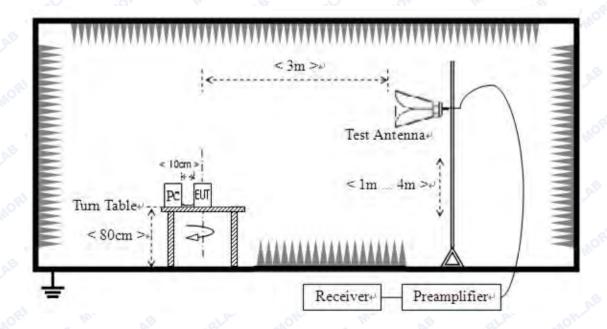
3.2.2. Radiated Emission

A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz





The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3maway from the Test Antenna, which is mounted on avariable height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
MXE EMIReceiver	Agilent	N9038A	MY54130016	2016.01.13	2017.01.12
Semi-Anechoic Chamber	Changning	9m*6m*6m	N/A	2016.01.13	2017.01.12
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2016.01.13	2017.01.12
Test Antenna - Horn	Schwarzbeck	BBHA9120C	9120C-384	2016.01.13	2017.01.12



4. 47 CFR Part 15B Requirements

4.1. Conducted Emission

4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the ACpower line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a 50μ H/50 Ω line impedance stabilization network (LISN).

Frequency range	Conducted Limit (dBµV)			
(MHz)	Quasi-peak	Average		
0.15 - 0.50	66 to 56	56 to 46		
0.50 - 5	56	46		
5 - 30	60	50		

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

4.1.2. Test Description

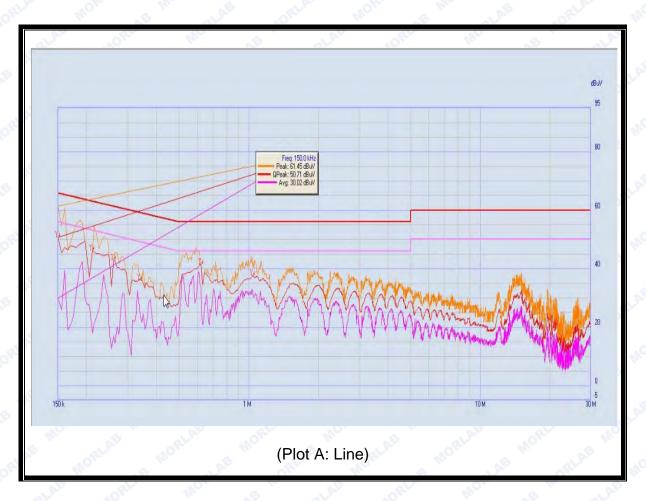
See section 3.2.1 of this report.

4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

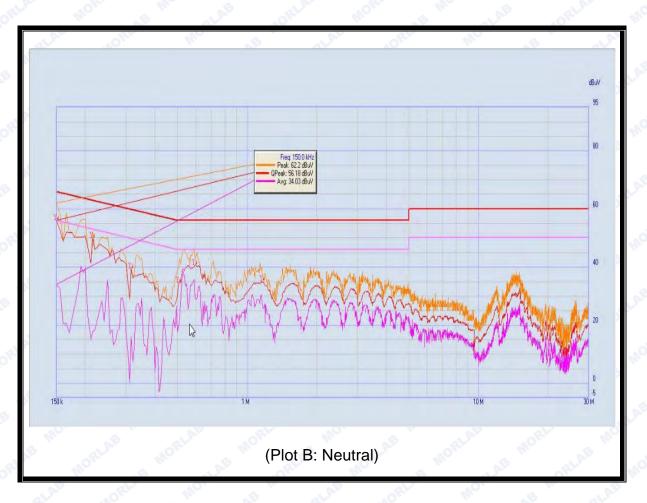
A. Test Plot and Suspicious Points:





NO.	Fre.	Emission Le	vel (dBµV)	Limit (d	dΒμV)	Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		
1	0.15	50.71	30.02	66.00	56.00	ORLA	PASS
2	0.21	46.30	17.97	64.29	54.29	Line	PASS
3	0.26	42.95	16.98	62.86	52.86		PASS
4	0.34	36.24	24.22	60.57	50.57		PASS
5	0.62	41.55	33.60	56.00	46.00		PASS
6	1.035	37.49	32.53	56.00	46.00	ORLAN	PASS





NO.	Fre. (MHz)	Emission Level (dBµV)		Limit (dBµV)		Power-line	Verdict
		Quai-peak	Average	Quai-peak	Average		
1	0.15	56.18	34.03	66.00	56.00	ORLA	PASS
2	0.215	49.91	17.73	64.14	54.14	e me	PASS
3	0.315	39.42	16.14	61.29	51.29	Mautral	PASS
4	0.505	34.77	19.51	56.00	46.00	Neutral	PASS
5	0.595	40.75	29.26	56.00	46.00	Okr. B W	PASS
6	1.165	35.07	26.85	56.00	46.00	ORLA	PASS

Test Result: PASS



4.2. Radiated Emission

4.2.1. Requirement

According to FCC section 15.109(a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency	Field Strength Limitation at 3m Measurement Dist					
range (MHz)	(μV/m)	(dBµV/m)				
30.0 - 88.0	100	20log 100				
88.0 - 216.0	150	20log 150				
216.0 - 960.0	200	20log 200				
Above 960.0	500	20log 500				

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBμV/m is calculated by 20log Emission Level(μV/m).
- 3) If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of Ld1 = Ld2 * (d2/d1)^{2.}

Example:

F.S Limit at 30m distance is $30\mu\text{V/m}$, then F.S Limitation at 3m distance is adjusted as Ld1 = L1 = $30\mu\text{V/m}$ * $(10)^2$ = 100 * $30\mu\text{V/m}$

4.2.2. Test Description

See section 3.2.2 of this report.



4.2.3. Frequency range of measurement

According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:

Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measure- ment range (MHz)
Below 1.705	30. 1000. 2000. 5000. 5th harmonic of the highest frequency or 40 GHz, whichever is lower.

4.2.4. Test Result

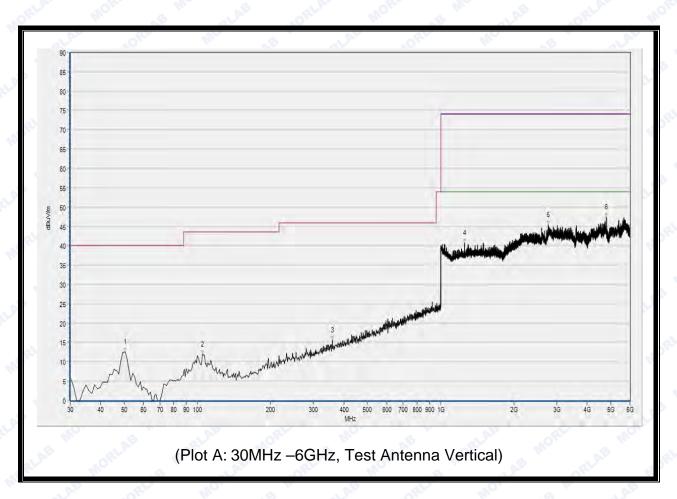
The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

The amplitude of spurious emissions which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

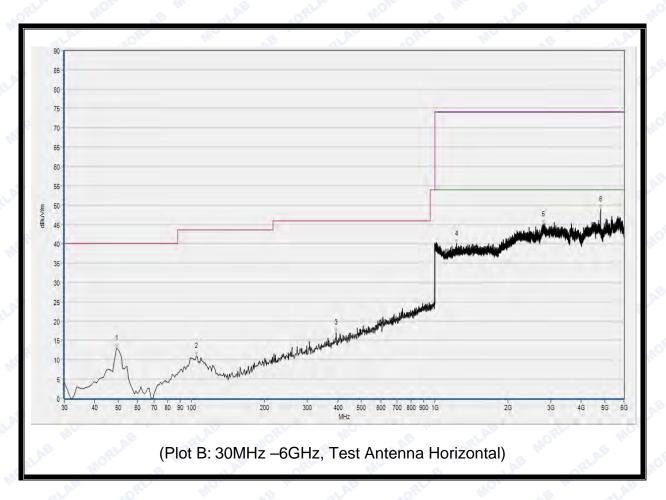
A. Test Plots and Suspicious Points:





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	2LAB	ORL
1	50.370	N.A.	12.54	N.A.	N.A.	40.00	N.A.	٧	PASS
2	104.690	N.A.	11.92	N.A.	N.A.	43.50	N.A.	V	PASS
3	358.830	N.A.	15.54	N.A.	N.A.	46.00	N.A.	V	PASS
4	1255.467	40.71	N.A.	34.25	74.00	N.A.	54.00	V	PASS
5	2770.240	45.35	N.A.	39.11	74.00	N.A.	54.00	V	PASS
6	4805.440	47.42	N.A.	41.81	74.00	N.A.	54.00	V	PASS





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	LAB	ORI
10	49.400	N.A.	13.12	N.A.	N.A.	40.00	N.A.	Н	PASS
2	104.690	N.A.	10.98	N.A.	N.A.	43.50	N.A.	Н	PASS
3	393.750	N.A.	17.15	N.A.	N.A.	46.00	N.A.	ΑĤ	PASS
4	1228.267	40.02	N.A.	34.70	74.00	N.A.	54.00	Н	PASS
5	2795.840	45.06	N.A.	39.02	74.00	N.A.	54.00	H	PASS
6	4806.720	48.91	N.A.	42.53	74.00	N.A.	54.00	H	PASS

Test Result: PASS

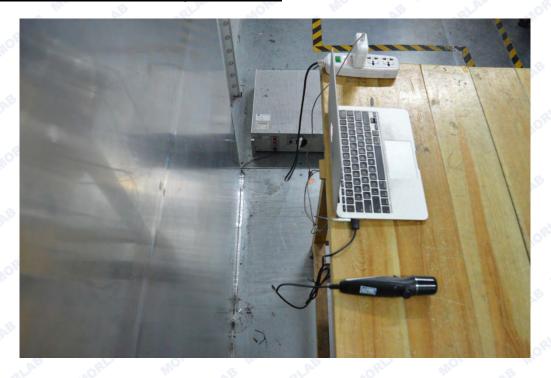


Annex A Photographs of Test Setup

1. Conducted emission main's port side view



2. Conducted emission main's port side view

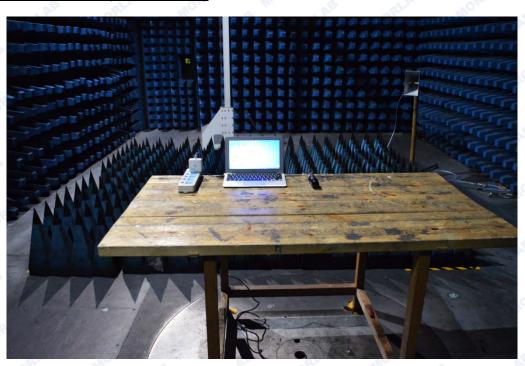




3. Radiated emission (30MHz-1GHz)



4. Radiated emission (Above 1GHz)





Annex B Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB





Annex C Testing Laboratory Information

1. Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.			
Department:	Morlab Laboratory			
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China			
Responsible Test Lab Manager:	Mr. Su Feng			
Telephone:	+86 755 36698555			
Facsimile:	+86 755 36698525			

2. Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd.
MORL MO. AB	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang
AL. MO. OF IL.	Road, Block 67, BaoAn District, ShenZhen, GuangDong
TLAS ORLAS MOR	Province, P. R. China

3. Accreditation Certificate

Accredited Testing Laboratory: The FCC registration number is 695796.

(Shenzhen Morlab Communications Technology Co., Ltd.)

4. Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

***** END OF REPORT *****

